

Search Notes

Application/Control No.

10/726,045

Examiner

John Q. Nguyen

Applicant(s)/Patent under
Reexamination

BAYER ET AL.

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
Previous	search updated	12/10/05	JN
242	423 423.1	↓	↓
242	423.2	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR